

<b>Search Notes</b>  	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10074996	LEE ET AL.
<b>Examiner</b>	<b>Art Unit</b>	
Christopher A Revak	2431	

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
none	none	1/31/09	CR

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
BRS Text Search: USPAT, US PGPUB, USOCR, DERWENT, IBM TDB, EPO, JPO, FPRS (see attached search strategy)	1/31/09; 7/22/09; 10/14/09	CR
DIALOG Text Search: COMPSCI, ELECTRON, SOFTWARE (see attached search strategy)	7/22/09; 10/14/09	CR
Interference Search (see attached search strategy)	10/14/09	CR

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
713	160,161,164-167,189,193,194	10/14/09	CR
726	16-20,26	10/14/09	CR
705	50-52,57-59	10/14/09	CR